

用于过压和欠压检测且具有内部基准的 TPS3701 高压 (36V) 窗口电压检测器

1 特性

- 宽电源电压范围：1.8V 至 36V
- 可调节阈值：低至 400mV
- 用于过压和欠压检测的漏极开路输出
- 低静态电流：7 μ A（典型值）
- 高阈值精度：
 - 工作温度范围内精度为 0.75%
 - 0.25%（典型值）
- 内部迟滞：5.5mV（典型值）
- 温度范围：-40°C 至 125°C
- 封装：
 - SOT-6

2 应用

- 工业控制系统
- 嵌入式计算模块
- DSP、微控制器和微处理器
- 笔记本电脑和台式机
- 便携式电池供电类产品
- FPGA 和 ASIC 系统

3 说明

TPS3701 宽电源电压窗口检测器在 1.8V 至 36V 的电压范围内运行。此器件具有两个内部基准电压为 400mV 的精密比较器和两个额定电压为 25V 的漏极开路输出（OUTA 和 OUTB），用于过压和欠压检测。可将 TPS3701 用作一个窗口电压检测器，也可以作为两个单独的电压监控器；使用外部电阻器设定监控电压。

当 INA 引脚的电压降至负向阈值以下时，OUTA 被驱动为低电平；当 INA 引脚的电压升至正向阈值以上时，OUTA 被驱动为高电平。当 INB 引脚的电压升至正向阈值以上时，OUTB 被驱动为低电平；而 INB 引脚的电压降至负向阈值以下时，OUTB 被驱动为高电平。TPS3701 的两个比较器均内置有滞后特性，可抑制噪声，避免触发错误，从而确保运行输出稳定。

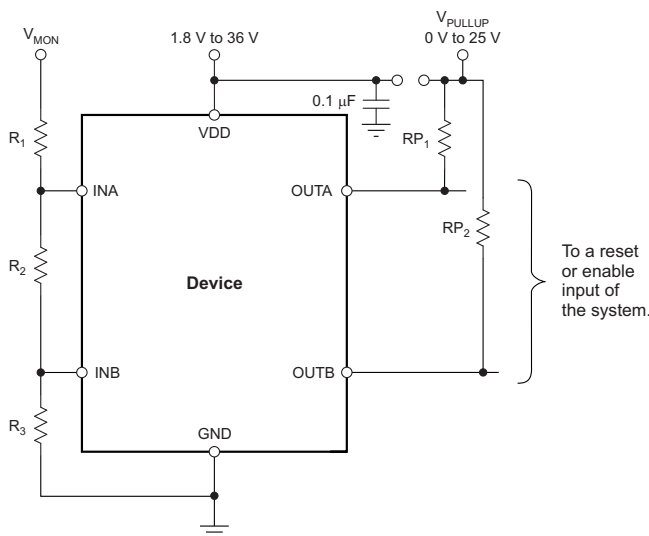
TPS3701 采用 SOT-6 封装，额定工作结温范围为 -40°C 至 125°C。

器件信息(1)

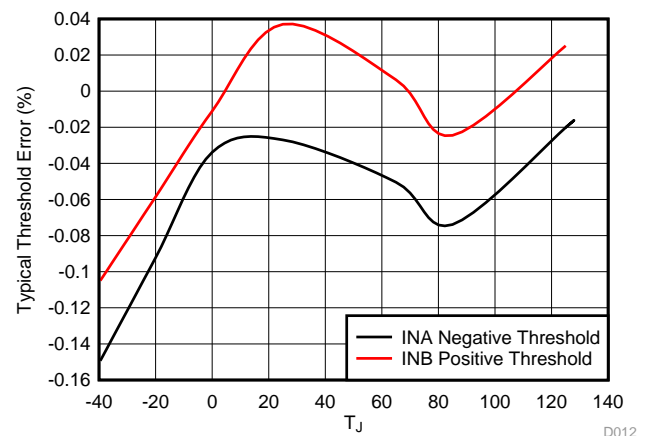
器件型号	封装	封装尺寸（标称值）
TPS3701	SOT (6)	2.90mm × 1.60mm

(1) 如需了解所有可用封装，请参阅产品说明书末尾的封装选项附录。

典型应用



典型误差与结温之间的关系



D012



目录

1 特性 1 2 应用 1 3 说明 1 4 修订历史记录 2 5 Pin Configuration and Functions 3 6 Specifications 4 6.1 Absolute Maximum Ratings 4 6.2 ESD Ratings 4 6.3 Recommended Operating Conditions 4 6.4 Thermal Information 4 6.5 Electrical Characteristics 5 6.6 Timing Requirements 6 6.7 Typical Characteristics 7 7 Detailed Description 10 7.1 Overview 10 7.2 Functional Block Diagram 10 7.3 Feature Description 11	7.4 Device Functional Modes 11 8 Application and Implementation 12 8.1 Application Information 12 8.2 Typical Application 16 9 Power Supply Recommendations 18 10 Layout 19 10.1 Layout Guidelines 19 10.2 Layout Example 19 11 器件和文档支持 20 11.1 文档支持 20 11.2 接收文档更新通知 20 11.3 社区资源 20 11.4 商标 20 11.5 静电放电警告 20 11.6 术语表 20 12 机械、封装和可订购信息 20
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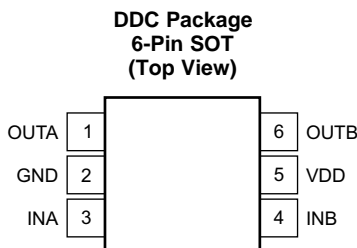
4 修订历史记录

Changes from Revision B (June 2018) to Revision C	Page
• 已更改 将文本“监控器”更改为“电压检测器”	1
• Changed "supervisor" to "voltage detector"	12

Changes from Revision A (November 2017) to Revision B	Page
• 已更改 将整个数据表中的文本“窗口比较器”更改为“窗口监控器”	1

Changes from Original (November 2014) to Revision A	Page
• Changed input pin voltage maximum from: 1.7 V to: 6.5 V	4
• Added a tablenote for the input pin voltage maximum	4
• Changed Figure 19	12

5 Pin Configuration and Functions



Pin Functions

PIN		I/O	DESCRIPTION
NAME	NO.		
GND	2	—	Ground
INA	3	I	Comparator A input. This pin is connected to the voltage to be monitored with the use of an external resistor divider. When the voltage at this terminal drops below the threshold voltage $V_{IT-(INA)}$, OUTA is driven low.
INB	4	I	Comparator B input. This pin is connected to the voltage to be monitored with the use of an external resistor divider. When the voltage at this terminal exceeds the threshold voltage $V_{IT+(INB)}$, OUTB is driven low.
OUTA	1	O	INA comparator open-drain output. OUTA is driven low when the voltage at this comparator is less than $V_{IT-(INA)}$. The output goes high when the sense voltage rises above $V_{IT+(INA)}$.
OUTB	6	O	INB comparator open-drain output. OUTB is driven low when the voltage at this comparator exceeds $V_{IT+(INB)}$. The output goes high when the sense voltage falls below $V_{IT-(INB)}$.
VDD	5	I	Supply voltage input. Connect a 1.8-V to 36-V supply to VDD to power the device. It is good analog design practice to place a 0.1- μ F ceramic capacitor close to this pin.

6 Specifications

6.1 Absolute Maximum Ratings

Over operating junction temperature range, unless otherwise noted.⁽¹⁾

		MIN	MAX	UNIT
Voltage ⁽²⁾	V _{DD}	-0.3	+40	V
	V _{OUTA} , V _{OUTB}	-0.3	+28	
	V _{INA} , V _{INB}	-0.3	+7	
Current	Output pin current		40	mA
Temperature	Operating junction, T _J	-40	+125	°C
	Storage temperature, T _{stg}	-65	+150	

- (1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) All voltages are with respect to network ground terminal.

6.2 ESD Ratings

		VALUE	UNIT
V _(ESD) Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	±2000	V
	Charged-device model (CDM), per JEDEC specification JESD22-C101 ⁽²⁾	±500	

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating junction temperature range (unless otherwise noted)

		MIN	NOM	MAX	UNIT
V _{DD}	Supply pin voltage	1.8		36	V
V _{INA} , V _{INB}	Input pin voltage	0		6.5 ⁽¹⁾	V
V _{OUTA} , V _{OUTB}	Output pin voltage	0		25	V
I _{OUTA} , I _{OUTB}	Output pin current	0		10	mA
T _J	Junction temperature	-40	+25	+125	°C

- (1) Operating V_{INA} or V_{INB} at 2.4 V or higher and at 125°C continuously for 10 years or more would cause a degradation of accuracy spec to 1.5% maximum

6.4 Thermal Information

THERMAL METRIC ⁽¹⁾		TPS3701	UNIT
		DDC (SOT)	
		6 PINS	
R _{θJA}	Junction-to-ambient thermal resistance	201.6	°C/W
R _{θJC(top)}	Junction-to-case (top) thermal resistance	47.8	°C/W
R _{θJB}	Junction-to-board thermal resistance	51.2	°C/W
ψ _{JT}	Junction-to-top characterization parameter	0.7	°C/W
ψ _{JB}	Junction-to-board characterization parameter	50.8	°C/W
R _{θJC(bot)}	Junction-to-case (bottom) thermal resistance	N/A	°C/W

- (1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report (SPRA953).

6.5 Electrical Characteristics

Over the operating temperature range of $T_J = -40^\circ\text{C}$ to $+125^\circ\text{C}$, $1.8\text{ V} \leq V_{DD} < 36\text{ V}$, and pull-up resistors $R_{P_{1,2}} = 100\text{ k}\Omega$, unless otherwise noted. Typical values are at $T_J = 25^\circ\text{C}$ and $V_{DD} = 12\text{ V}$.

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
V_{DD}	Supply voltage range		1.8		36	V
$V_{(POR)}$	Power-on reset voltage ⁽¹⁾	$V_{OL} \leq 0.2\text{ V}$			0.8	V
$V_{IT-(INA)}$	INA pin negative input threshold voltage	$V_{DD} = 1.8\text{ V to } 36\text{ V}$	397	400	403	mV
$V_{IT+(INA)}$	INA pin positive input threshold voltage	$V_{DD} = 1.8\text{ V to } 36\text{ V}$	400	405.5	413	mV
$V_{HYS(INA)}$	INA pin hysteresis voltage ($HYS = V_{IT+(INA)} - V_{IT-(INA)}$)		2	5.5	12	mV
$V_{IT-(INB)}$	INB pin negative input threshold voltage	$V_{DD} = 1.8\text{ V to } 36\text{ V}$	387	394.5	400	mV
$V_{IT+(INB)}$	INB pin positive input threshold voltage	$V_{DD} = 1.8\text{ V to } 36\text{ V}$	397	400	403	mV
$V_{HYS(INB)}$	INB pin hysteresis voltage ($HYS = V_{IT+(INB)} - V_{IT-(INB)}$)		2	5.2	12	mV
V_{OL}	Low-level output voltage	$V_{DD} = 1.8\text{ V}, I_{OUT} = 3\text{ mA}$		130	250	mV
		$V_{DD} = 5\text{ V}, I_{OUT} = 5\text{ mA}$		150	250	mV
I_{IN}	Input current (at INA, INB pins)	$V_{DD} = 1.8\text{ V and } 36\text{ V}, V_{INA}, V_{INB} = 6.5\text{ V}$	-25	+1	+25	nA
		$V_{DD} = 1.8\text{ V and } 36\text{ V}, V_{INA}, V_{INB} = 0.1\text{ V}$	-15	+1	+15	nA
$I_{D(leak)}$	Open-drain output leakage current	$V_{DD} = 1.8\text{ V and } 36\text{ V}, V_{OUT} = 25\text{ V}$		10	300	nA
I_{DD}	Supply current	$V_{DD} = 1.8\text{ V} - 36\text{ V}$		8	11	μA
UVLO	Undervoltage lockout ⁽²⁾	V_{DD} falling	1.3	1.5	1.7	V

(1) The lowest supply voltage (V_{DD}) at which output is active; $t_{r(VDD)} > 15\text{ }\mu\text{s/V}$. If less than $V_{(POR)}$, the output is undetermined.

(2) When V_{DD} falls below UVLO, OUTA is driven low and OUTB goes to high impedance. The outputs cannot be determined if less than $V_{(POR)}$.

6.6 Timing Requirements

PARAMETER	TEST CONDITION	MIN	TYP	MAX	UNIT
$t_{pd(HL)}$	High-to-low propagation delay ⁽¹⁾ $V_{DD} = 24\text{ V}$, $\pm 10\text{-mV}$ input overdrive, $R_L = 100\text{ k}\Omega$, $V_{OH} = 0.9 \times V_{DD}$, $V_{OL} = 250\text{ mV}$		9.9		μs
$t_{pd(LH)}$	Low-to-high propagation delay ⁽¹⁾ $V_{DD} = 24\text{ V}$, $\pm 10\text{-mV}$ input overdrive, $R_L = 100\text{ k}\Omega$, $V_{OH} = 0.9 \times V_{DD}$, $V_{OL} = 250\text{ mV}$		28.1		μs
$t_{d(start)}$ ⁽²⁾	Startup delay $V_{DD} = 5\text{ V}$		155		μs
t_r	Output rise time $V_{DD} = 12\text{ V}$, 10-mV input overdrive, $R_L = 100\text{ k}\Omega$, $C_L = 10\text{ pF}$, $V_O = (0.1\text{ to }0.9) \times V_{DD}$		2.7		μs
t_f	Output fall time $V_{DD} = 12\text{ V}$, 10-mV input overdrive, $R_L = 100\text{ k}\Omega$, $C_L = 10\text{ pF}$, $V_O = (0.9\text{ to }0.1) \times V_{DD}$		0.12		μs

- (1) High-to-low and low-to-high refers to the transition at the input pins (INA and INB).
- (2) During power on, V_{DD} must exceed 1.8 V for at least 150 μs (typical) before the output state reflects the input condition.

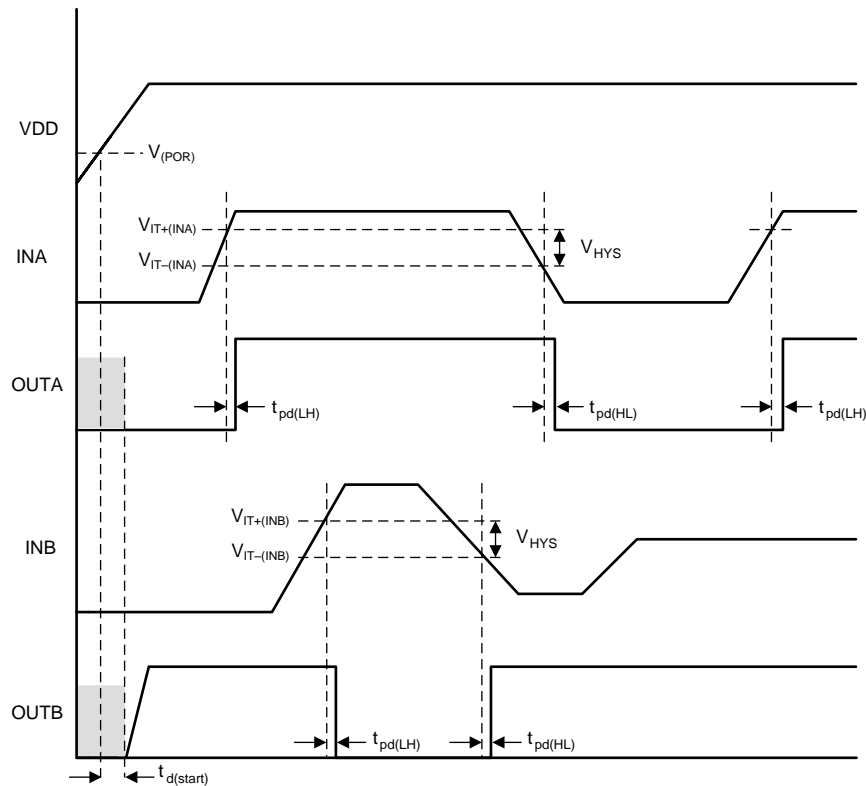


Figure 1. Timing Diagram

6.7 Typical Characteristics

At $T_J = 25^\circ\text{C}$ and $V_{DD} = 12\text{ V}$, unless otherwise noted.

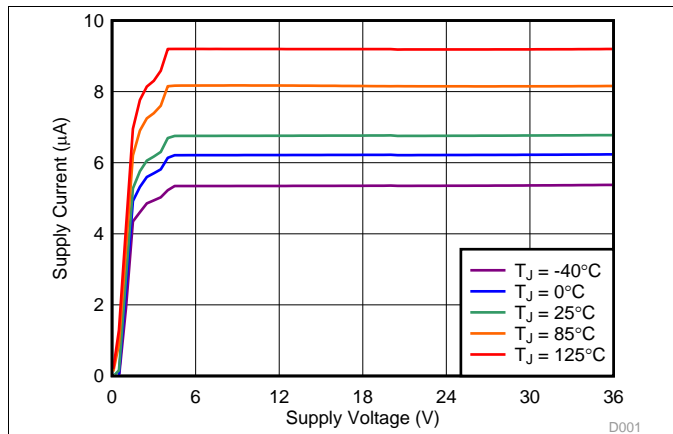


Figure 2. Supply Current vs Supply Voltage

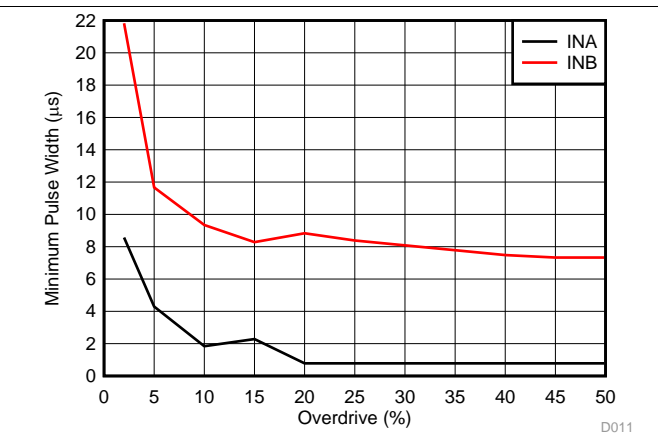


Figure 3. Minimum Pulse Duration vs Threshold Overdrive Voltage⁽¹⁾ (1)

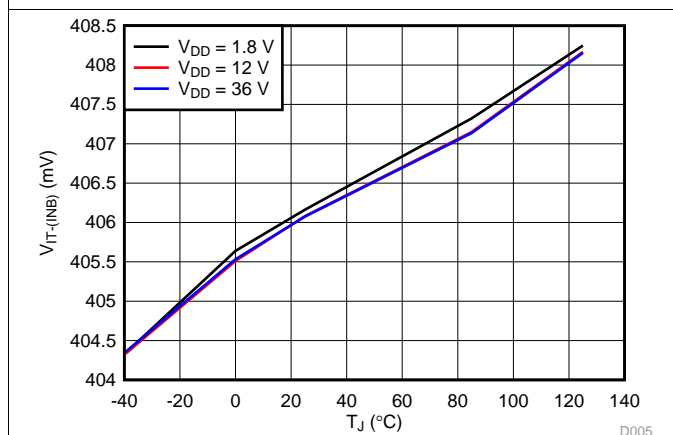


Figure 4. INA Positive Input Threshold Voltage ($V_{IT+(INA)}$) vs Temperature

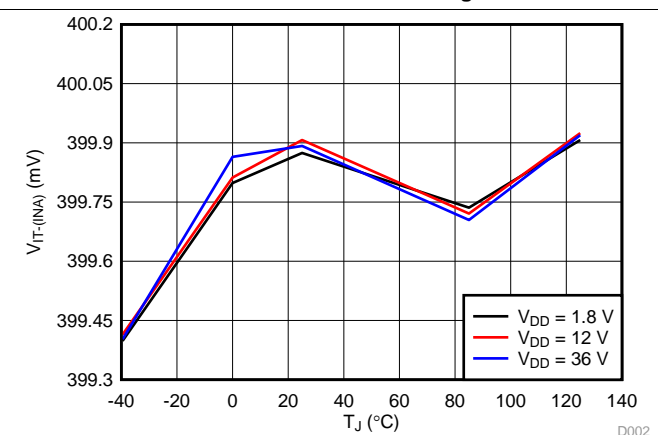


Figure 5. INA Negative Input Threshold Voltage ($V_{IT-(INA)}$) vs Temperature

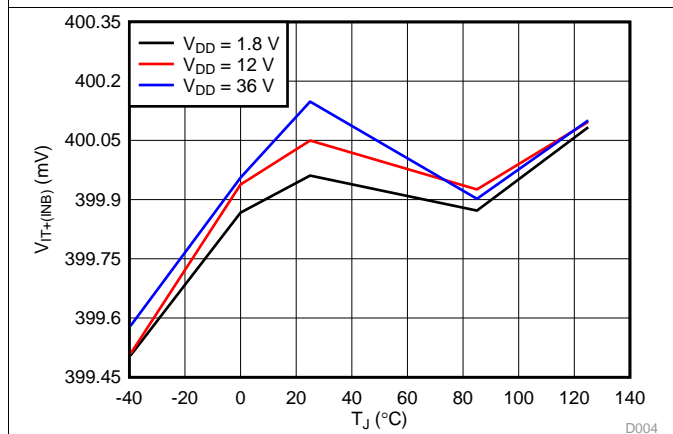


Figure 6. INB Positive Input Threshold Voltage ($V_{IT+(INB)}$) vs Temperature

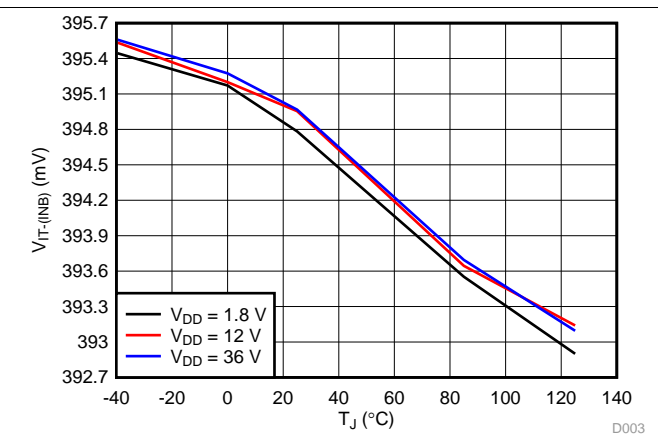


Figure 7. INB Negative Input Threshold Voltage ($V_{IT-(INB)}$) vs Temperature

(1) Minimum pulse duration required to trigger output high-to-low transition. INA = negative spike below V_{IT-} and INB = positive spike above V_{IT+} .

Typical Characteristics (continued)

At $T_J = 25^\circ\text{C}$ and $V_{DD} = 12\text{ V}$, unless otherwise noted.

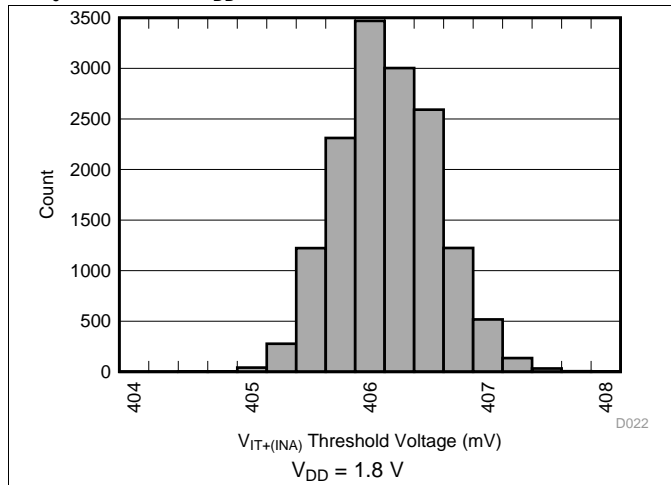


Figure 8. INA Positive Input Threshold Voltage ($V_{IT+(INA)}$) Distribution

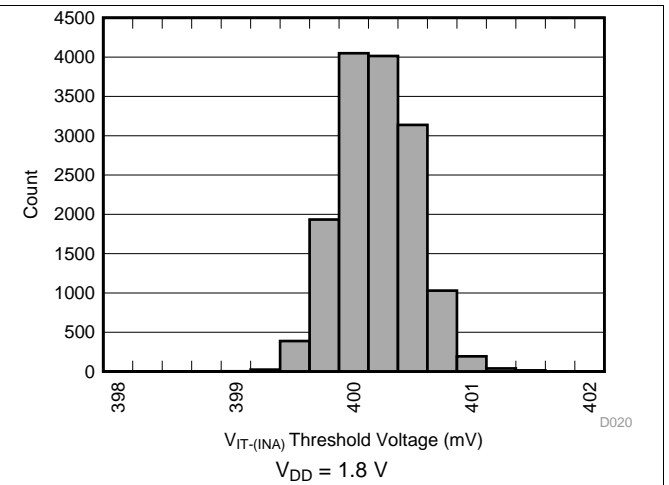


Figure 9. INA Negative Input Threshold Voltage ($V_{IT-(INA)}$) Distribution

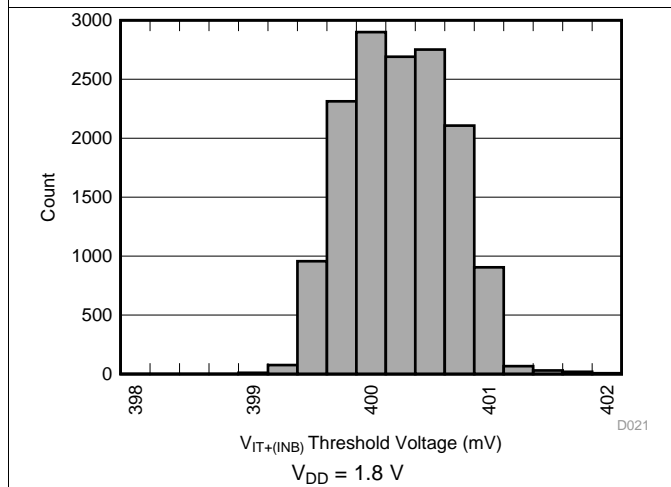


Figure 10. INB Positive Input Threshold Voltage ($V_{IT+(INB)}$) Distribution

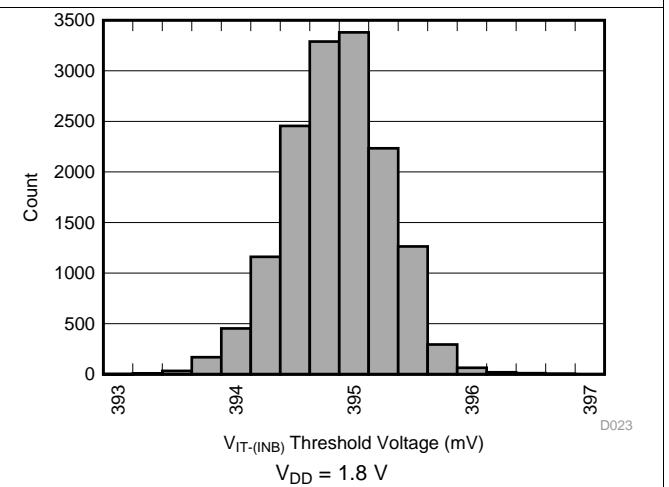


Figure 11. INB Negative Input Threshold Voltage ($V_{IT-(INB)}$) Distribution

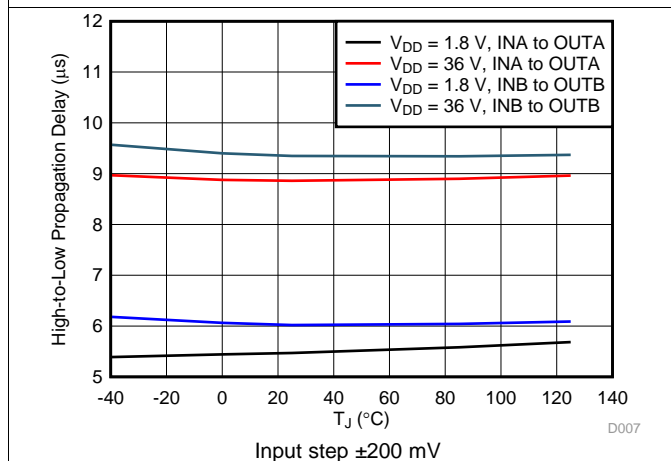


Figure 12. Propagation Delay vs Temperature (High-to-Low Transition at the Inputs)

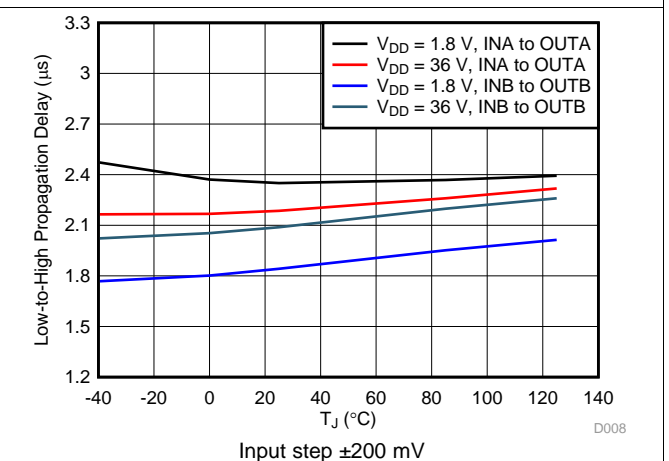


Figure 13. Propagation Delay vs Temperature (Low-to-High Transition at the Inputs)

Typical Characteristics (continued)

At $T_J = 25^\circ\text{C}$ and $V_{DD} = 12\text{ V}$, unless otherwise noted.

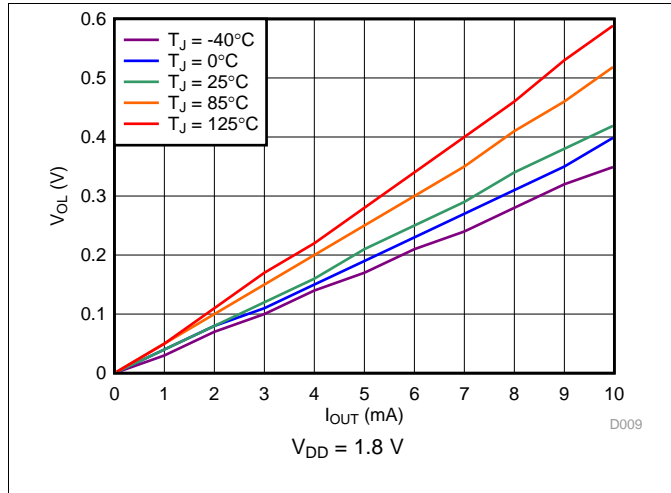


Figure 14. Output Voltage Low vs Output Sink Current

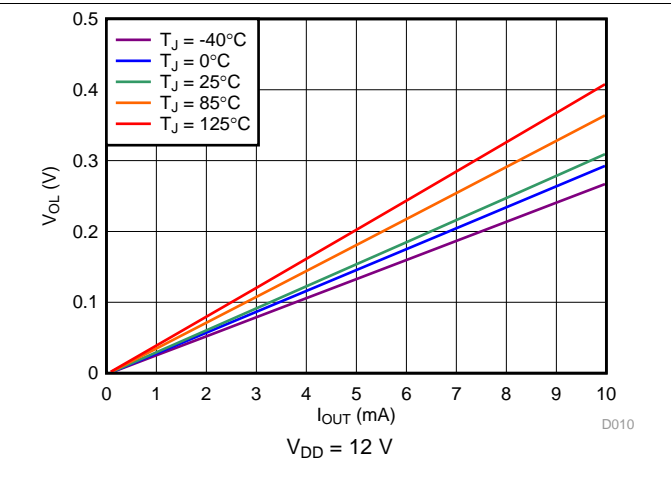


Figure 15. Output Voltage Low vs Output Sink Current

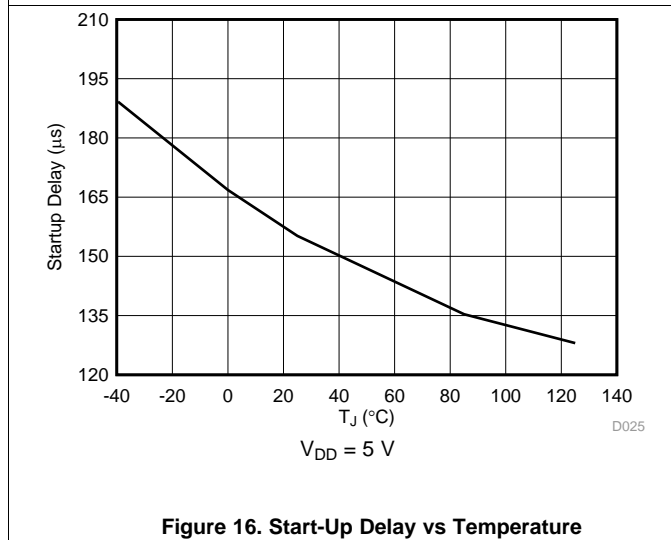


Figure 16. Start-Up Delay vs Temperature

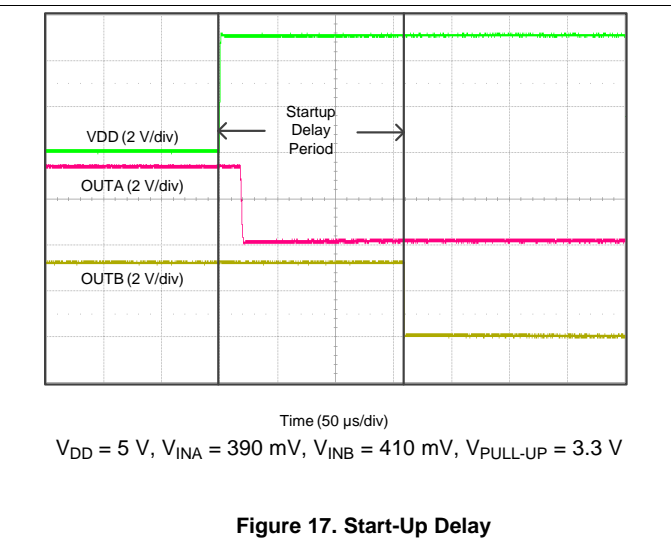


Figure 17. Start-Up Delay

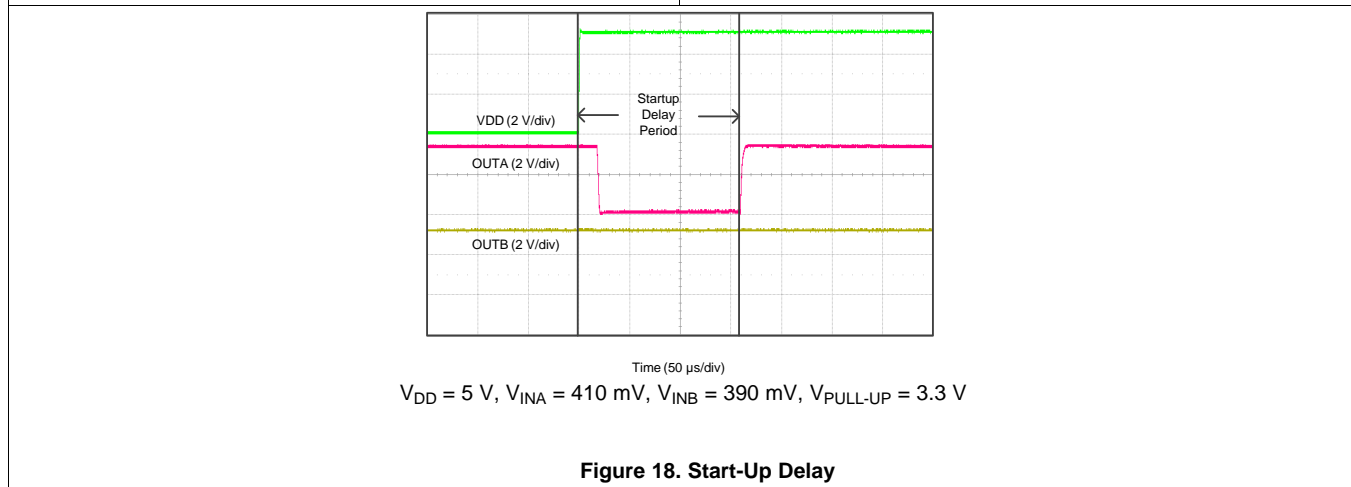


Figure 18. Start-Up Delay

7 Detailed Description

7.1 Overview

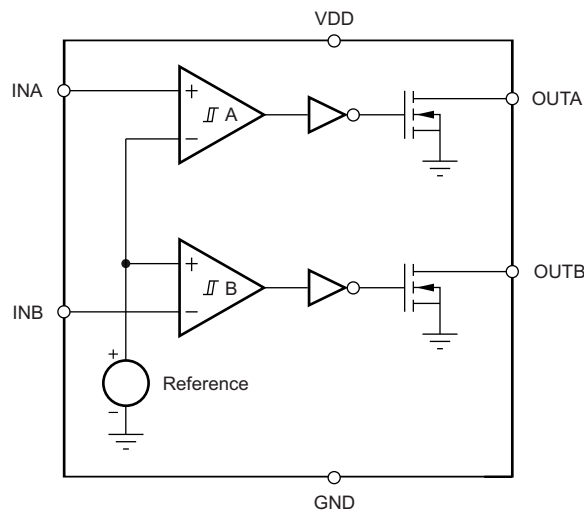
The TPS3701 combines two comparators (referred to as A and B) and a precision reference for over- and undervoltage detection. The TPS3701 features a wide supply voltage range (1.8 V to 36 V) and high-accuracy window threshold voltages of 400 mV (0.75% over temperature) with built-in hysteresis. The outputs are rated to 25 V and can sink up to 10 mA.

Set each input pin (INA, INB) to monitor any voltage above 0.4 V by using an external resistor divider network. Each input pin has very low input leakage current, allowing the use of large resistor dividers without sacrificing system accuracy. To form a window voltage detector, use the two input pins and three resistors (see the [Window Voltage Detector Considerations](#) section). In this configuration, the TPS3701 is designed to assert the output signals when the monitored voltage is within the window band. Each input can also be used independently. The relationship between the inputs and the outputs is shown in [Table 1](#). Broad voltage thresholds are supported that enable the device to be used in a wide array of applications.

Table 1. Truth Table

CONDITION	OUTPUT	STATUS
$INA > V_{IT+(INA)}$	OUTA high	Output A high impedance
$INA < V_{IT-(INA)}$	OUTA low	Output A asserted
$INB > V_{IT+(INB)}$	OUTB low	Output B asserted
$INB < V_{IT-(INB)}$	OUTB high	Output B high impedance

7.2 Functional Block Diagram



7.3 Feature Description

7.3.1 Inputs (INA, INB)

The TPS3701 combines two comparators with a precision reference voltage. Each comparator has one external input; the other input is connected to the internal reference. The rising threshold on INB and the falling threshold on INA are designed and trimmed to be equal to the reference voltage (400 mV). This configuration optimizes the device accuracy when used as a window voltage detector. Both comparators also have built-in hysteresis that proves immunity to noise and ensures stable operation.

The INA and INB inputs swings from ground to 1.7 V (7.0 V absolute maximum), regardless of the device supply voltage used. Although not required in most cases, it is good analog design practice to place a 1-nF to 10-nF bypass capacitor at the comparator input for noisy applications in order to reduce sensitivity to transient voltage changes on the monitored signal.

For comparator A, the corresponding output (OUTA) is driven to logic low when the input INA voltage drops below $V_{IT-(INA)}$. When the voltage exceeds $V_{IT+(INA)}$, OUTA goes to a high-impedance state; see [Figure 1](#).

For comparator B, the corresponding output (OUTB) is driven to logic low when the voltage at input INB exceeds $V_{IT+(INB)}$. When the voltage drops below $V_{IT-(INB)}$ OUTB goes to a high-impedance state; see [Figure 1](#). Together, these two comparators form a window voltage detector function as described in the [Window Voltage Detector Considerations](#) section.

7.3.2 Outputs (OUTA, OUTB)

In a typical TPS3701 application, the outputs are connected to a reset or enable input of the processor [such as a digital signal processor (DSP), application-specific integrated circuit (ASIC), or other processor type] or the outputs are connected to the enable input of a voltage regulator [such as a DC-DC converter or low-dropout regulator (LDO)].

The TPS3701 provides two open-drain outputs (OUTA and OUTB); use pull-up resistors to hold these lines high when the output goes to a high-impedance state. Connect pull-up resistors to the proper voltage rails to enable the outputs to be connected to other devices at correct interface voltage levels. The TPS3701 outputs can be pulled up to 25 V, independent of the device supply voltage. To ensure proper voltage levels, give some consideration when choosing the pull-up resistor values. The pull-up resistor value is determined by V_{OL} , output capacitive loading, and output leakage current ($I_{D(leak)}$). These values are specified in the [Electrical Characteristics](#) table. Use wired-OR logic to merge OUTA and OUTB into one logic signal.

[Table 1](#) and the [Inputs \(INA, INB\)](#) section describe how the outputs are asserted or high impedance. See [Figure 1](#) for a timing diagram that describes the relationship between threshold voltages and the respective output.

7.4 Device Functional Modes

7.4.1 Normal Operation ($V_{DD} > UVLO$)

When the voltage on VDD is greater than 1.8 V for at least 155 μ s, the OUTA and OUTB signals correspond to the voltage on INA and INB as listed in [Table 1](#).

7.4.2 Undervoltage Lockout ($V_{(POR)} < V_{DD} < UVLO$)

When the voltage on VDD is less than the device UVLO voltage, and greater than the power-on-reset voltage, $V_{(POR)}$, the OUTA and OUTB signals are asserted and high impedance, respectively, regardless of the voltage on INA and INB.

7.4.3 Power-On-Reset ($V_{DD} < V_{(POR)}$)

When the voltage on VDD is lower than the required voltage to internally pull the asserted output to GND ($V_{(POR)}$), both outputs are in a high-impedance state.

8 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

8.1 Application Information

The TPS3701 is used as a precision dual-voltage detector in several different configurations. The monitored voltage (V_{MON}), VDD voltage, and output pull-up voltage can be independent voltages or connected in any configuration. The following sections show the connection configurations and the voltage limitations for each configuration.

8.1.1 Window Voltage Detector Considerations

The inverting and noninverting configuration of the comparators forms a window voltage detector circuit using a resistor divider network, as shown in Figure 19 and Figure 20. The input pins can monitor any system voltage above 400 mV with the use of a resistor divider network. INA and INB monitor for undervoltage and overvoltage conditions, respectively.

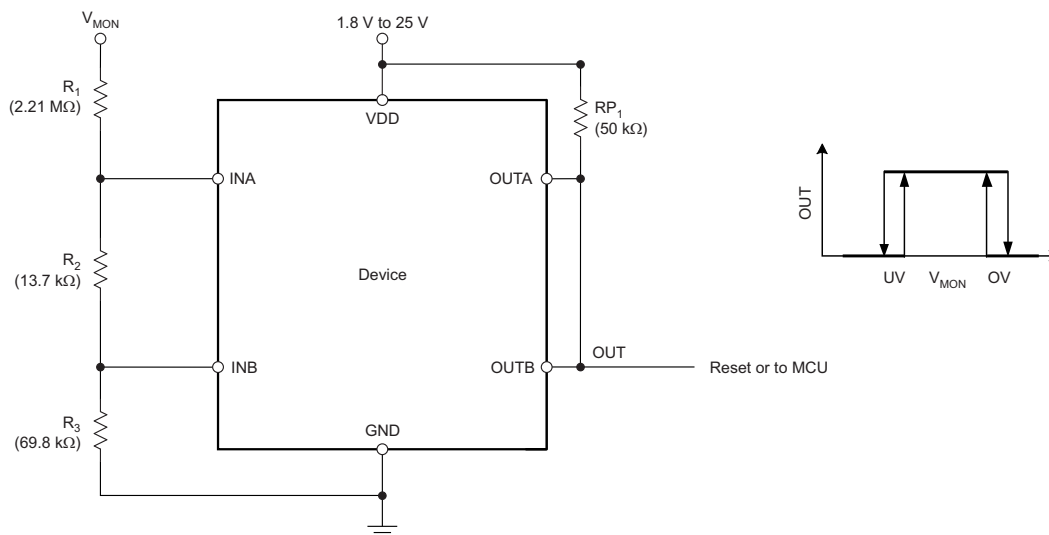


Figure 19. Window Voltage Detector Block Diagram

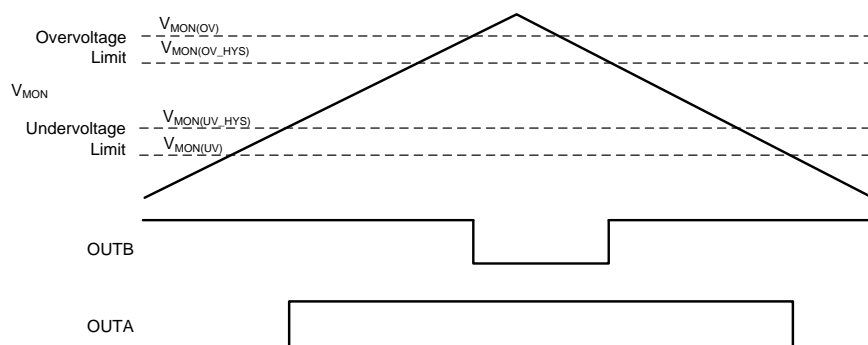


Figure 20. Window Voltage Detector Timing Diagram

Application Information (continued)

The TPS3701 flags the overvoltage or undervoltage condition with the greatest accuracy. The highest accuracy threshold voltages are $V_{IT-(INA)}$ and $V_{IT+(INB)}$, and correspond with the falling undervoltage flag, and the rising overvoltage flag, respectively. These thresholds represent the accuracy when the monitored voltage is within the valid window (both OUTA and OUTB are in a high-impedance state), and correspond to the $V_{MON(UV)}$ and $V_{MON(OV)}$ trigger voltages, respectively. If the monitored voltage is outside of the valid window (V_{MON} is less than the undervoltage limit, $V_{MON(UV)}$, or greater than overvoltage limit, $V_{MON(OV)}$), then the input threshold voltages to re-enter the valid window are $V_{IT+(INA)}$ or $V_{IT-(INB)}$, and correspond with the $V_{MON(UV_HYS)}$ and $V_{MON(OV_HYS)}$ monitored voltages, respectively.

The resistor divider values and target threshold voltage can be calculated by using [Equation 1](#) through [Equation 4](#):

$$R_{TOTAL} = R_1 + R_2 + R_3 \quad (1)$$

Choose an R_{TOTAL} value so that the current through the divider is approximately 100 times higher than the input current at the INA and INB pins. Resistors with high values minimize current consumption; however, the input bias current degrades accuracy if the current through the resistors is too low. See application report [SLVA450, Optimizing Resistor Dividers at a Comparator Input](#) (SLVA450), for details on sizing input resistors.

R_3 is determined by [Equation 2](#):

$$R_3 = \frac{R_{TOTAL}}{V_{MON(OV)}} \cdot V_{IT+(INB)}$$

where

- $V_{MON(OV)}$ is the target voltage at which an overvoltage condition is detected. (2)

R_2 is determined by either [Equation 3](#) or [Equation 4](#):

$$R_2 = \left[\frac{R_{TOTAL}}{V_{MON(UV_HYS)}} \cdot V_{IT+(INA)} \right] - R_3$$

where

- $V_{MON(UV_HYS)}$ is the target voltage at which an undervoltage condition is removed as V_{MON} rises. (3)

$$R_2 = \left[\frac{R_{TOTAL}}{V_{MON(UV)}} \cdot V_{IT-(INA)} \right] - R_3$$

where

- $V_{MON(UV)}$ is the target voltage at which an undervoltage condition is detected. (4)

8.1.2 Input and Output Configurations

[Figure 21](#) to [Figure 24](#) show examples of the various input and output configurations.

Application Information (continued)

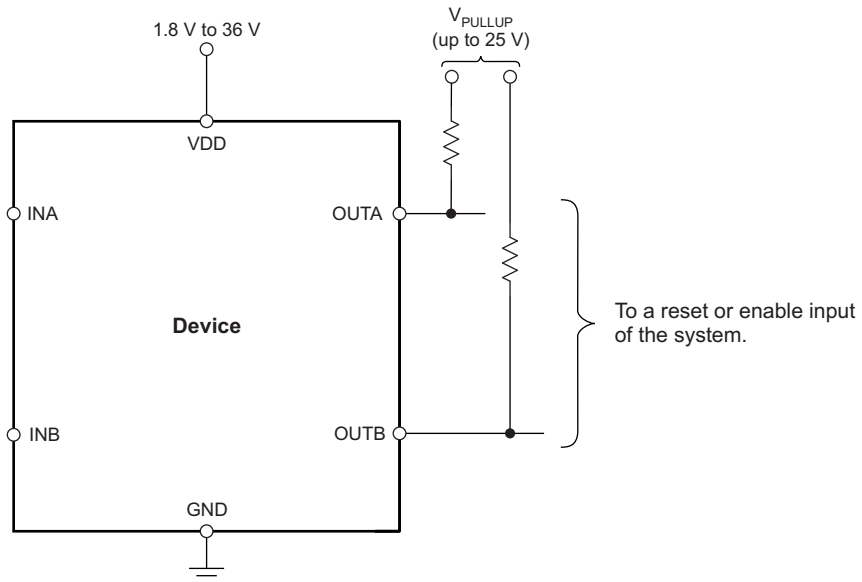


Figure 21. Interfacing to Voltages Other than V_{DD}

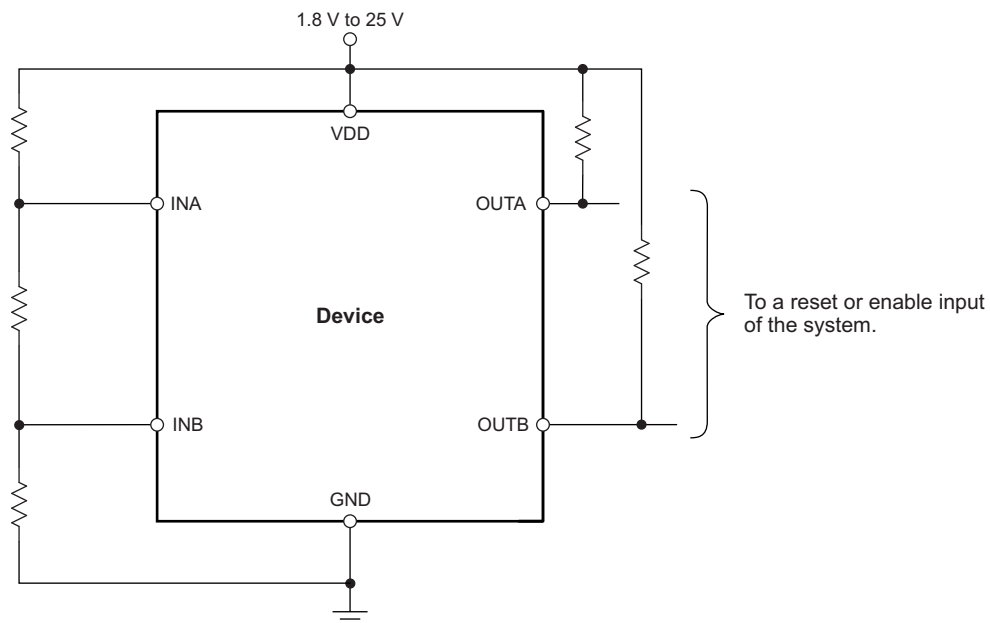
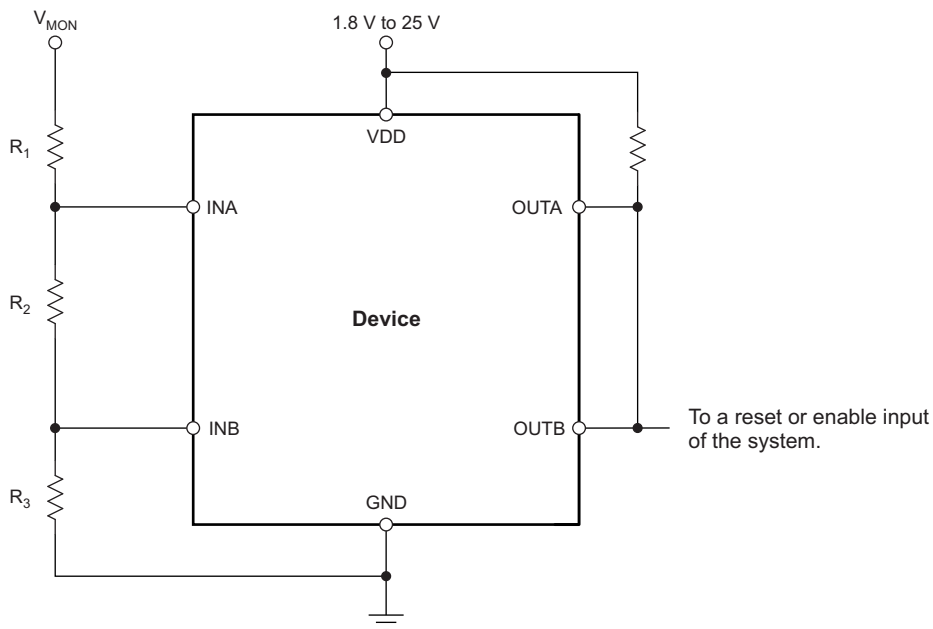


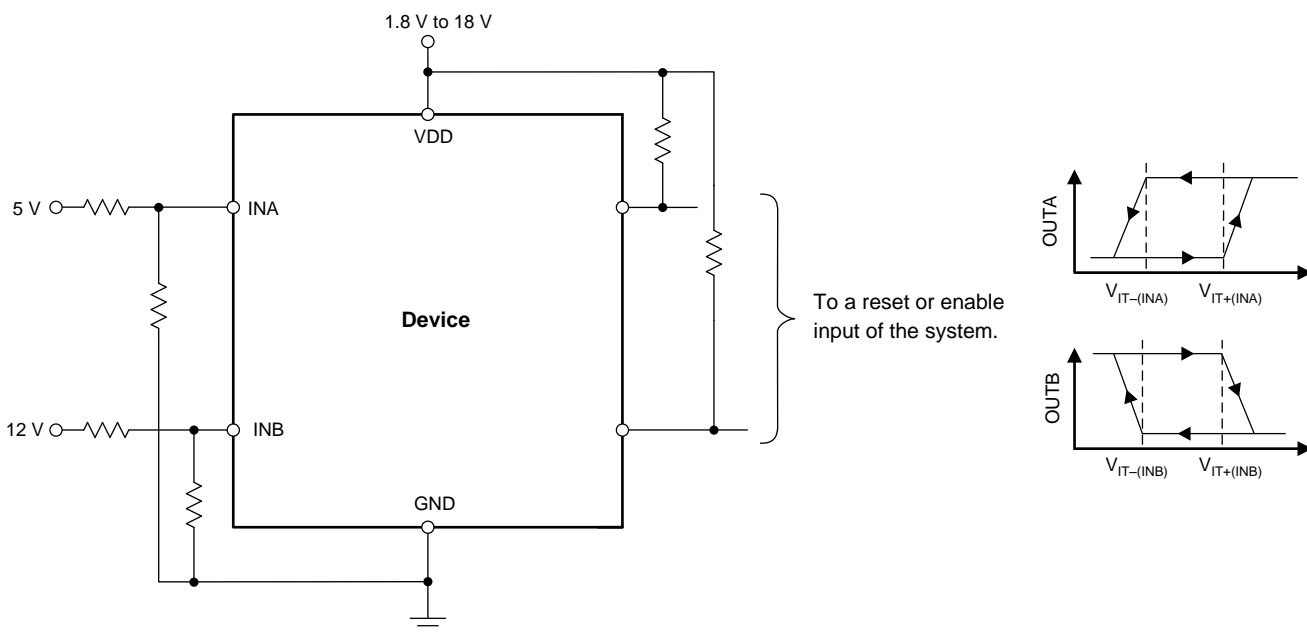
Figure 22. Monitoring the Same Voltage as V_{DD}

Application Information (continued)



NOTE: The inputs can monitor a voltage higher than $V_{DD} (max)$ with the use of an external resistor divider network.

Figure 23. Monitoring a Voltage Other than V_{DD}



NOTE: In this case, OUTA is driven low when an undervoltage condition is detected at the 5-V rail and OUTB is driven low when an overvoltage condition is detected at the 12-V rail.

Figure 24. Monitoring Overvoltage for One Rail and Undervoltage for a Different Rail

8.1.3 Immunity to Input Pin Voltage Transients

The TPS3701 is immune to short voltage transient spikes on the input pins. Sensitivity to transients depends on both transient duration and amplitude; see Figure 3, *Minimum Pulse Duration vs Threshold Overdrive Voltage*.

8.2 Typical Application

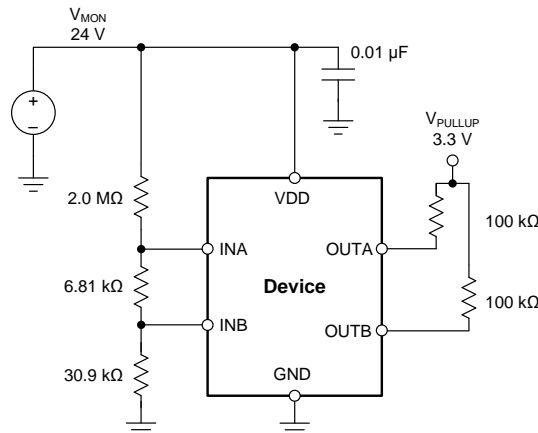


Figure 25. 24-V, 10% Window Voltage Detector

8.2.1 Design Requirements

Table 2 lists the design parameters for this example.

Table 2. Design Parameters

PARAMETER	DESIGN REQUIREMENT	DESIGN RESULT
Monitored voltage	24-V nominal, rising ($V_{MON(OV)}$) and falling ($V_{MON(UV)}$) threshold $\pm 10\%$ nominal (26.4 V and 21.6 V, respectively)	$V_{MON(OV)} = 26.4 \text{ V} \pm 2.7\%$, $V_{MON(UV)} = 21.6 \text{ V} \pm 2.7\%$
Output logic voltage	3.3-V CMOS	3.3-V CMOS
Maximum current consumption	30 μA	24 μA

8.2.2 Detailed Design Procedure

- Determine the minimum total resistance of the resistor network necessary to achieve the current consumption specification by using Equation 1. For this example, the current flow through the resistor network was chosen to be 13 μA ; a lower current can be selected. However, take care to avoid leakage currents that are artifacts of the manufacturing process. Leakage currents significantly impact the accuracy if they are greater than 1% of the resistor network current.

$$R_{TOTAL} = \frac{V_{MON(OV)}}{I} = \frac{26.4 \text{ V}}{13 \mu\text{A}} = 2.03 \text{ M}\Omega$$

where

- $V_{MON(OV)}$ is the target voltage at which an overvoltage condition is detected as V_{MON} rises.
- I is the current flowing through the resistor network. (5)

- After R_{TOTAL} is determined, R_3 can be calculated using Equation 6. Select the nearest 1% resistor value for R_3 . In this case, 30.9 k Ω is the closest value.

$$R_3 = \frac{R_{TOTAL}}{V_{MON(OV)}} \cdot V_{IT+(INB)} = \frac{2.03 \text{ M}\Omega}{26.4 \text{ V}} \cdot 0.4 \text{ V} = 30.7 \text{ k}\Omega \quad (6)$$

- Use Equation 7 to calculate R_2 . Select the nearest 1% resistor value for R_2 . In this case, 6.81 k Ω is the closest value.

$$R_2 = \frac{R_{TOTAL}}{V_{MON(UV)}} \cdot V_{IT-(INA+)} - R_3 = \frac{2.03 \text{ M}\Omega}{21.6 \text{ V}} \cdot 0.4 \text{ V} - 30.9 \text{ k}\Omega = 6.69 \text{ k}\Omega \quad (7)$$

- Use Equation 8 to calculate R_1 . Select the nearest 1% resistor value for R_1 . In this case, 2 M Ω is the closest value.

$$R_1 = R_{\text{TOTAL}} - R_2 - R_3 = 2.03 \text{ M}\Omega - 6.81 \text{ k}\Omega - 30.9 \text{ k}\Omega = 1.99 \text{ M}\Omega \quad (8)$$

5. The worst-case tolerance can be calculated by referring to Equation 13 in application report [Optimizing Resistor Dividers at a Comparator Input](#) (SLVA450). An example of the rising threshold error, $V_{\text{MON(OV)}}$, is given in Equation 9:

$$\% \text{ ACC} = \% \text{ TOL}(V_{\text{IT+(INB)}}) + 2 \cdot \left(1 - \frac{V_{\text{IT+(INB)}}}{V_{\text{MON(OV)}}} \right) \cdot \% \text{ TOL}_R = 0.75 \% + 2 \cdot \left(1 - \frac{0.4}{26.4} \right) \cdot 1\% = 2.72 \%$$

where

- $\% \text{ TOL}(V_{\text{IT+(INB)}})$ is the tolerance of the INB positive threshold.
- $\% \text{ ACC}$ is the total tolerance of the $V_{\text{MON(OV)}}$ voltage.
- $\% \text{ TOL}_R$ is the tolerance of the resistors selected. (9)

6. When the outputs switch to the high-Z state, the rise time of the OUTA or OUTB node depends on the pull-up resistance and the capacitance on the node. Choose pull-up resistors that satisfy the downstream timing requirements; 100-k Ω resistors are a good choice for low-capacitive loads.

8.2.3 Application Curve

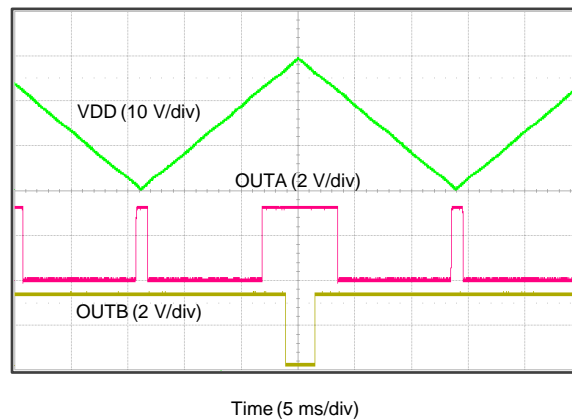


Figure 26. 24-V Window Monitor Output Response

9 Power Supply Recommendations

The TPS3701 has a 40-V absolute maximum rating on the VDD pin, with a recommended operating condition of 36 V. If the voltage supply that is providing power to VDD is susceptible to any large voltage transient that may exceed 40 V, or if the supply exhibits high voltage slew rates greater than 1 V/ μ s, take additional precautions. Place an RC filter between the supply and VDD to filter any high-frequency transient surges on the VDD pin. A 100- Ω resistor and 0.01- μ F capacitor is required in these cases, as shown in [Figure 27](#).

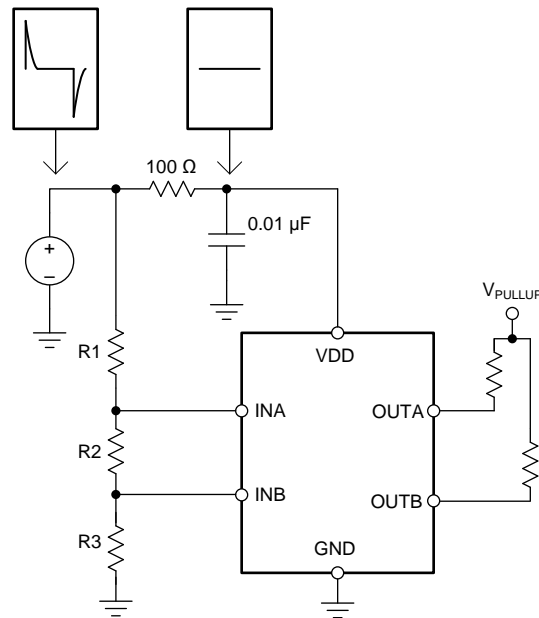


Figure 27. Using an RC Filter to Remove High-Frequency Disturbances on VDD

10 Layout

10.1 Layout Guidelines

- Place R_1 , R_2 , and R_3 close to the device to minimize noise coupling into the INA and INB nodes.
- Place the VDD decoupling capacitor close to the device.
- Avoid using long traces for the VDD supply node. The VDD capacitor (C_{VDD}), along with parasitic inductance from the supply to the capacitor, may form an LC tank and create ringing with peak voltages above the maximum VDD voltage. If this is unavoidable, see [Figure 27](#) for an example of filtering VDD.

10.2 Layout Example

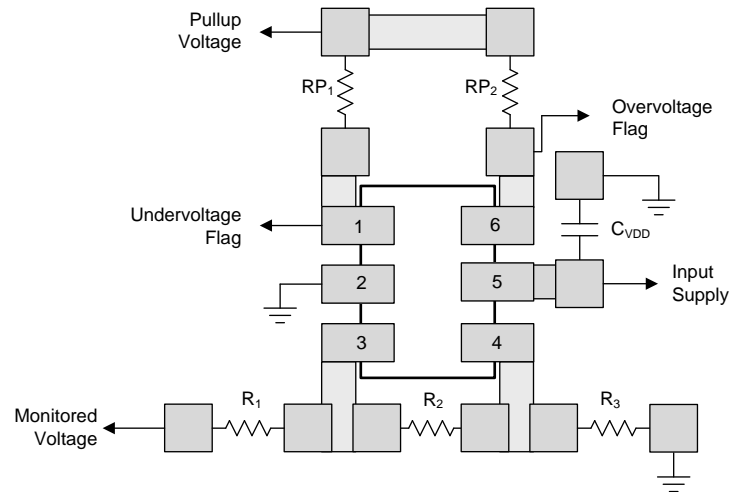


Figure 28. Recommended Layout

11 器件和文档支持

11.1 文档支持

11.1.1 相关文档

相关文档，请参见以下应用报告和用户指南（可从 TI 网站获取）：

- 应用报告 《将 TPS3700 用作负轨过压和欠压检测器》(SLVA600)。
- 应用报告 《优化比较器输入上的电阻分压器》(SLVA450)。
- 用户指南 《TPS3700EVM-114 评估模块》(SLVU683)。

11.2 接收文档更新通知

要接收文档更新通知，请导航至 TI.com.cn 上的器件产品文件夹。单击右上角的 [通知我](#) 进行注册，即可每周接收产品信息更改摘要。有关更改的详细信息，请查看任何已修订文档中包含的修订历史记录。

11.3 社区资源

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ESD 的损坏小至导致微小的性能降级，大至整个器件故障。精密的集成电路可能更容易受到损坏，这是因为非常细微的参数更改都可能会导致器件与其发布的规格不相符。

11.6 术语表

SLYZ022 — TI 术语表。

这份术语表列出并解释术语、缩写和定义。

12 机械、封装和可订购信息

以下页面包含机械、封装和可订购信息。这些信息是指定器件的最新可用数据。数据如有变更，恕不另行通知，且不会对此文档进行修订。如需获取此产品说明书的浏览器版本，请查阅左侧的导航栏。

PACKAGING INFORMATION

Orderable part number	Status (1)	Material type (2)	Package Pins	Package qty Carrier	RoHS (3)	Lead finish/ Ball material (4)	MSL rating/ Peak reflow (5)	Op temp (°C)	Part marking (6)
TPS3701DDCR	Active	Production	SOT-23-THIN (DDC) 6	3000 LARGE T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-40 to 125	ZABO
TPS3701DDCT	Active	Production	SOT-23-THIN (DDC) 6	250 SMALL T&R	Yes	NIPDAU	Level-2-260C-1 YEAR	-	ZABO

(1) **Status:** For more details on status, see our [product life cycle](#).

(2) **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

(3) **RoHS values:** Yes, No, RoHS Exempt. See the [TI RoHS Statement](#) for additional information and value definition.

(4) **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

(5) **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

(6) **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "-" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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TAPE AND REEL INFORMATION



QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TPS3701DDCR	SOT-23-THIN	DDC	6	3000	179.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3
TPS3701DDCT	SOT-23-THIN	DDC	6	250	180.0	8.4	3.2	3.2	1.4	4.0	8.0	Q3

TAPE AND REEL BOX DIMENSIONS


*All dimensions are nominal

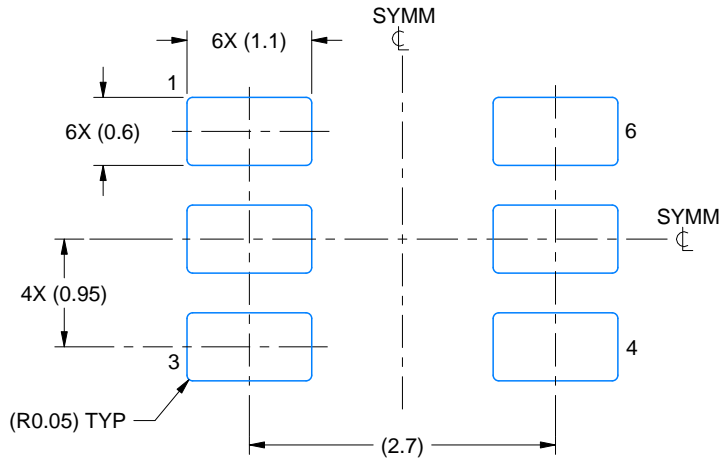
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TPS3701DDCR	SOT-23-THIN	DDC	6	3000	213.0	191.0	35.0
TPS3701DDCT	SOT-23-THIN	DDC	6	250	213.0	191.0	35.0

EXAMPLE BOARD LAYOUT

DDC0006A

SOT-23 - 1.1 max height

SMALL OUTLINE TRANSISTOR



LAND PATTERN EXAMPLE
EXPLODED METAL SHOWN
SCALE:15X



SOLDEMASK DETAILS

4214841/E 08/2024

NOTES: (continued)

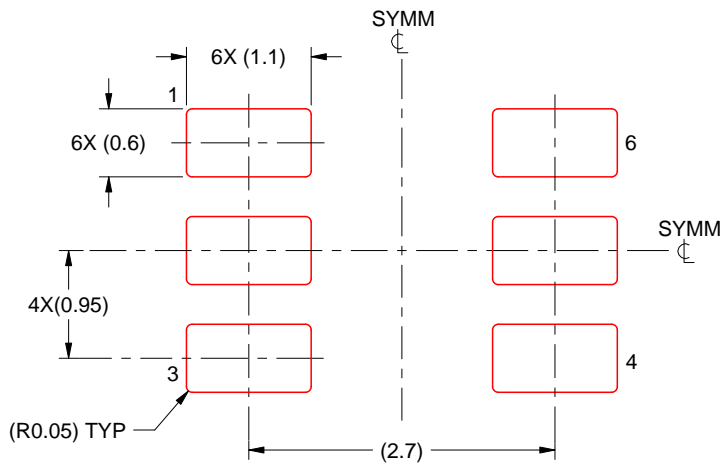
- 4. Publication IPC-7351 may have alternate designs.
- 5. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

DDC0006A

SOT-23 - 1.1 max height

SMALL OUTLINE TRANSISTOR



SOLDER PASTE EXAMPLE
BASED ON 0.125 THICK STENCIL
SCALE:15X

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NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
7. Board assembly site may have different recommendations for stencil design.

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